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- Ultrafast Operation . . . 7.6 ns (Typ)
- Low Positive Supply Current 10.6 mA (Typ)
- Operates From a Single 5-V Supply or From a Split ±5-V Supply
- Complementary Outputs
- Low Offset Voltage
- No Minimum Slew Rate Requirement
- Output Latch Capability
- Functional Replacement to the LT1016

# description

The TL3016 is an ultrafast comparator designed to interface directly to TTL logic while operating from either a single 5-V power supply or dual ±5-V supplies. It features extremely tight offset voltage and high gain for precision applications. It has complementary outputs that can be latched using the LATCH ENABLE terminal. Figure 1 shows the positive supply current of this comparator. The TL3016 only requires 10.6 mA (typical) to achieve a propagation delay of 7.6 ns.

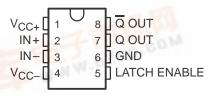
The TL3016 is a pin-for-pin functional replacement for the LT1016 comparator, offering higher speed operation but consuming half the power.

#### **AVAILABLE OPTIONS**

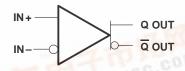
	PACKAG	CHIP		
TA	SMALL OUTLINE <sup>†</sup> (D)	TSSOP (PW)	FORM <sup>‡</sup> (Y)	
0°C to 70°C	TL3016CD	TL3016CPWLE	TL3016Y	
-40°C to 85°C	TL3016ID	TL3016IPWLE	_	

<sup>†</sup>The PW packages are available left-ended taped and reeled only.

#### D AND PW PACKAGE (TOP VIEW)



# symbol (each comparator)



# **POSITIVE SUPPLY CURRENT**

#### vs FREE-AIR TEMPERATURE

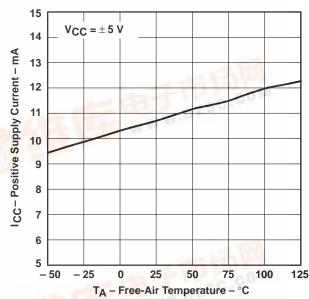


Figure 1

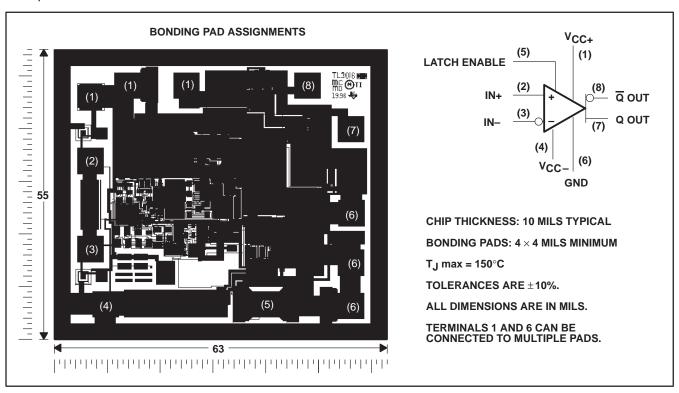
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

<sup>‡</sup>Chip forms are tested at T<sub>A</sub> = 25°C only.

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# **TL3016Y chip information**

This chip displays characteristics similar to the TL3016C. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.



COMPONENT COUNT						
Bipolars	53					
MOSFETs	49					
Resistors	46					
Capacitors	14					



# TL3016, TL3016Y ULTRA-FAST LOW-POWER PRECISION COMPARATORS

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# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>DD</sub> (see Note 1)	– 7 V to 7 V
Differential input voltage, V <sub>ID</sub> (see Note 2)	7 V
Input voltage range, V <sub>I</sub>	7 V
Input voltage, V <sub>I</sub> (LATCH ENABLE)	7 V
Output current, IO	±20 mA
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	–40°C to 85°C
Storage temperature range, T <sub>stq</sub>	– 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.

2. Differential voltages are at IN+ with respect to IN-.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
D	725 mW	5.8 mW/°C	464 mW
PW	525 mW	4.2 mW/°C	336 mW



# TL3016, TL3016Y ULTRA-FAST LOW-POWER PRECISION COMPARATORS SLCS130D - MARCH 1997 - REVISED MARCH 2000

# electrical characteristics at specified operating free-air temperature, $V_{DD}$ = $\pm 5$ V, $V_{LE}$ = 0 (unless otherwise noted)

$V_{\text{IO}}  \text{Input offset voltage}  \begin{array}{c ccccccccccccccccccccccccccccccccccc$	PARAMETER		TEST CONDITIONS†		TL3016C		TL3016I			UNIT		
Ta = full range   Ta = full		PARAWIETER	TEST CONDITIONS:		MIN	TYP‡	MAX	MIN	TYP <sup>‡</sup>	MAX	OIIII	
Tamperature coefficient of input offset voltage   Tamperature coefficient of input offset current   Tamperature coefficient of input offset current   Tamperature coefficient of input offset current   Tamperature coefficient of Tamperature coeffic	V10	Input offset voltage	T <sub>A</sub> = 25°C			0.5	3		0.5	3	m\/	
Input offset voltage   Input offset voltage   Input offset current	VIO IIIput oliset voltage		T <sub>A</sub> = full range				3.5			3.5	111 V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	ανιο					-4.8			-4.5		μV/°C	
Ta = full range	1	Input offset current	T <sub>A</sub> = 25°C			0.1	0.6		0.1	0.6		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	чо	input onset current	T <sub>A</sub> = full range				0.9			1.3	μΑ	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		Input higo ourrent	T <sub>A</sub> = 25°C			6	10		6	10		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	чв	input bias current	T <sub>A</sub> = full range				10			10	μΑ	
CMRR         Common-mode rejection ratio         -3.75 ≤ V <sub>IC</sub> ≤ 3.5 V, T <sub>A</sub> = 25°C         80         97         80         97         dB           k <sub>SVR</sub> Supply-voltage rejection ratio         Positive supply: 4.6 V ≤ +V <sub>DD</sub> ≤ 5.4 V, T <sub>A</sub> = 25°C         60         72         60         72         60         72         48         100         80         100         80         100         48         100         80         100         80         100         48         100         80         100         48         100         80         100         48         100         40         40         40         40         40         40         40         40         40         40         40         40         40         40         40	\/	Common-mode input	V <sub>DD</sub> = ±5 V		-3.75		3.5	-3.75		3.5		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	VICR	voltage range	V <sub>DD</sub> = 5 V		1.25		3.5	1.25		3.5	V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	CMRR		$-3.75 \le V_{IC} \le 3.5 \text{ V},$	T <sub>A</sub> = 25°C	80	97		80	97		dB	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	I KC//D	Supply-voltage rejection		$\leq$ +V <sub>DD</sub> $\leq$ 5.4 V,	60	72		60	72		dB	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$		ratio		$\leq$ $-$ V <sub>DD</sub> $\leq$ $-$ 2 V,	80	100		80	100			
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Voi	Low lovel output voltage	I <sub>(sink)</sub> = 4 mA, T <sub>A</sub> = 25°C	$V+ \le 4.6 V$ ,		500	600		500	600	m\/	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	VOL	Low-level output voltage	I <sub>(sink)</sub> = 10 mA, T <sub>A</sub> = 25°C	V+ ≤ 4.6 V,		750			750		mv	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Vou	High-level output voltage	- /	$I_O = 1 \text{ mA},$	3.6	3.9		3.6	3.9		V	
Negative supply current	VОН	r ligh-lever output voltage		$I_O = 10 \text{ mA},$	3.4	3.7		3.4	3.7		٧	
Negative supply current	Inn	Positive supply current	T <sub>A</sub> = full range			10.6	12.5		10.6	12.5	mΔ	
VIL (LATCH ENABLE)         0.8         0.8         V           VIH High-level input voltage (LATCH ENABLE)         2         2         V           Low-level input current         VLE = 0         0         1         0         1	טטי	Negative supply current		-1.8	-1.3		-2.4	-1.3		111/5		
VIH (LATCH ENABLE)  2  V  Low-level input current  VLE = 0  0  1  UA	VIL						0.8			0.8	V	
III Leave to the transfer of t	VIH				2			2			V	
11L (LATCH ENABLE) V <sub>LE</sub> = 2 V 24 39 24 45	lu.		V <sub>LE</sub> = 0			0	1		0	1	^	
	'IL 	(LATCH ENABLE)	V <sub>LE</sub> = 2 V			24	39		24	45	μΑ	

<sup>†</sup> Full range for the TL3016C is  $T_A = 0^{\circ}$ C to  $70^{\circ}$ C. Full range for the TL3016I is  $T_A = -40^{\circ}$ C to  $85^{\circ}$ C. ‡ All typical values are measures with  $T_A = 25^{\circ}$ C.

# switching characteristics, $V_{DD}$ = $\pm 5$ V, $V_{LE}$ = 0 (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		TL3016C			TL3016I			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	Olvil
tod4 Propagation delay time‡	$\Delta V_{I} = 100 \text{ mV},$	T <sub>A</sub> = 25°C		7.8	10		7.8	10		
	Propagation delay time‡	$V_{OD} = 5 \text{ mV}$	T <sub>A</sub> = full range		7.8	11.2		7.8	12.2	
		$\Delta V_I = 100 \text{ mV},$ $V_{OD} = 20 \text{ mV}$	T <sub>A</sub> = 25°C		7.6	10		7.6	10	ns
			T <sub>A</sub> = full range		7.6	11.2		7.6	12.2	
tsk(p)	Pulse skew ( t <sub>pd+</sub> - t <sub>pd-</sub>  )	$\Delta V_I = 100 \text{ mV},$ $T_A = 25^{\circ}\text{C}$	$V_{OD} = 5 \text{ mV},$		0.5			0.5		ns
t <sub>su</sub>	Setup time, LATCH ENABLE				2.5			2.5		ns

<sup>&</sup>lt;sup>†</sup> Full range for the TL3016C is 0°C to 70°C. Full range for the TL3016I is −40°C to 85°C.

### **TYPICAL CHARACTERISTICS**

# **Table of Graphs**

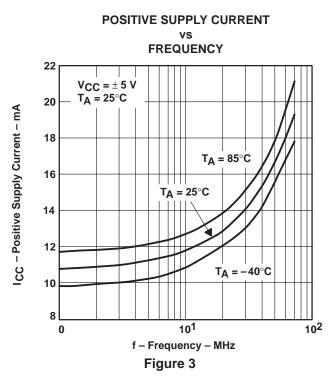
			FIGURE
		vs Input voltage	2
ICC	Positive supply current	vs Frequency	3
		vs Free-air temperature	4
ICC	Negative supply current	vs Free-air temperature	5
		vs Overdrive voltage	6
		vs Supply voltage	7
tpd	Propagation delay time	vs Input impedance	8
		vs Load capacitance	9
		vs Free-air temperature	10
VIC	Common-mode input voltage	vs Free-air temperature	11
	Input threshold voltage (LATCH ENABLE)	vs Free-air temperature	12
.,	Output voltage	vs Output source current	13
VО	Output voltage	vs Output sink current	14
lį	Input current (LATCH ENABLE)	vs Input voltage	15

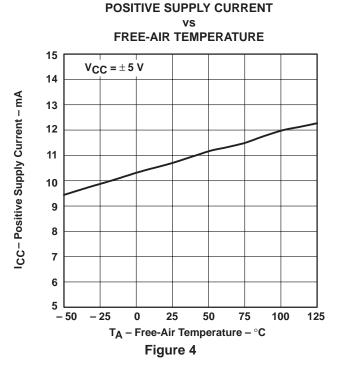


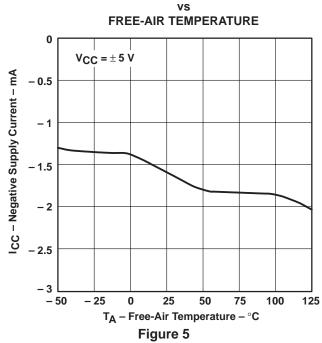
<sup>‡</sup>tpd1 cannot be measured in automatic handling equipment with low values of overdrive. The TL3016 is 100% tested with a 1-V step and 500-mV overdrive at  $T_A = 25^{\circ}$ C only. Correlation tests have shown that  $t_{pd1}$  limits given can be ensured with this test, if additional dc tests are performed to ensure that all internal bias conditions are correct. For low overdrive conditions,  $V_{OS}$  is added to the overdrive.

### **TYPICAL CHARACTERISTICS**

# **POSITIVE SUPPLY CURRENT** vs **INPUT VOLTAGE** 20 $V_{CC} = \pm 5 \stackrel{'}{V}$ $T_A = 25 ^{\circ}C$ 18 ICC - Positive Supply Current - mA 16 T<sub>A</sub> = 85°C 14 T<sub>A</sub> = 25°C 12 10 8 $T_A = -40^{\circ}C$ 6 2 0 2 V<sub>I</sub> - Input Voltage - V Figure 2





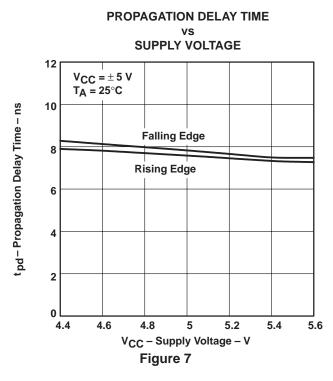


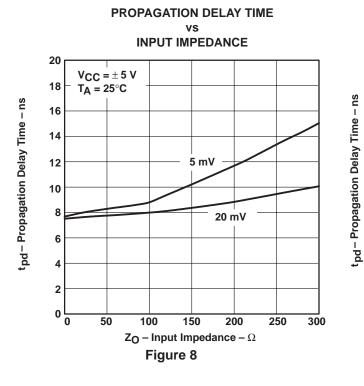
**NEGATIVE SUPPLY CURRENT** 

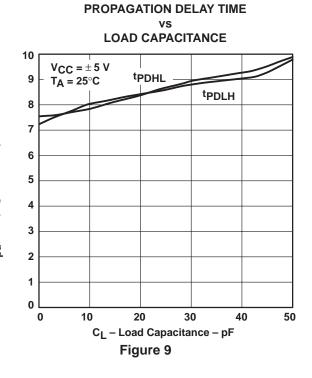


### **TYPICAL CHARACTERISTICS**

# **PROPAGATION DELAY TIME** vs **OVERDRIVE VOLTAGE** 10 $V_{CC} = \pm 5 V$ 9 T<sub>A</sub> = 25°C tpd- Propagation Delay Time - ns 8 7 6 5 4 3 2 1 0 10 40 50 Overdrive Voltage - mV Figure 6



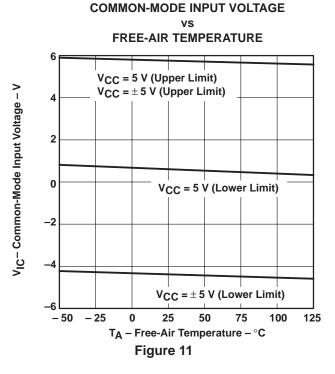


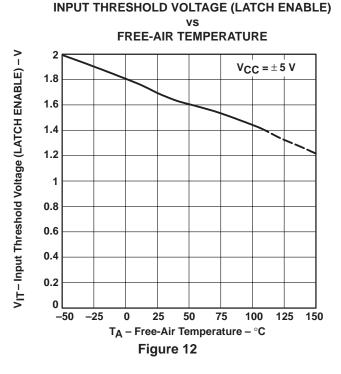


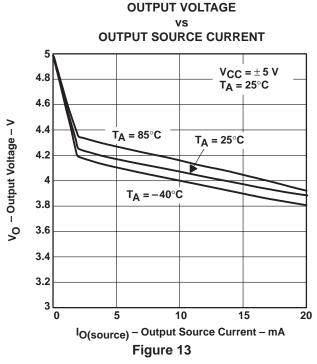


### **TYPICAL CHARACTERISTICS**

# **PROPAGATION DELAY TIME** FREE-AIR TEMPERATURE 25 $V_{CC} = \pm 5 V$ t pd - Propagation Delay Time - ns 20 15 10 **Rising Edge Falling Edge** 5 - 50 - 25 75 100 125 T<sub>A</sub> - Free-Air Temperature - °C Figure 10



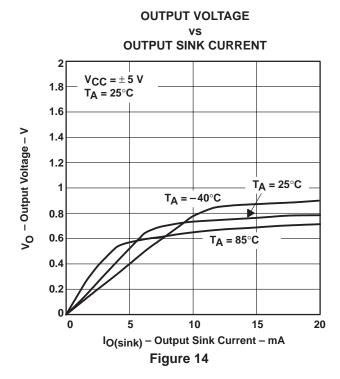


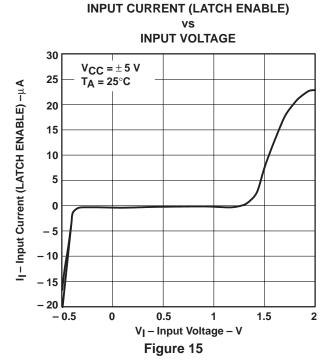




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### **TYPICAL CHARACTERISTICS**



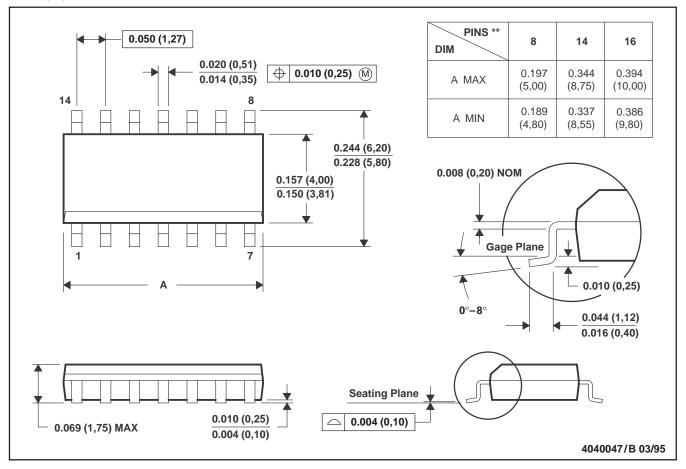


### **MECHANICAL INFORMATION**

# D (R-PDSO-G\*\*)

### PLASTIC SMALL-OUTLINE PACKAGE

#### 14 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
- D. Four center pins are connected to die mount pad.
- E. Falls within JEDEC MS-012

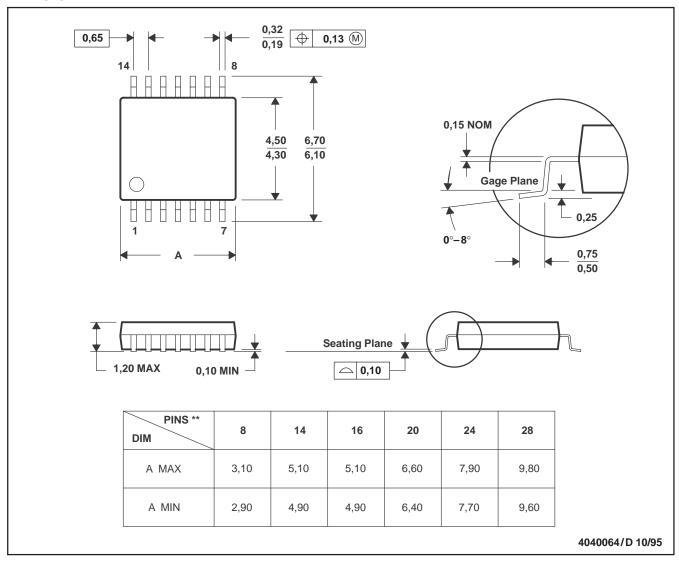


# MECHANICAL INFORMATION

# PW (R-PDSO-G\*\*)

## PLASTIC SMALL-OUTLINE PACKAGE

#### 14 PIN SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



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